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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	768
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	12000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 125°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx08a-tq144a

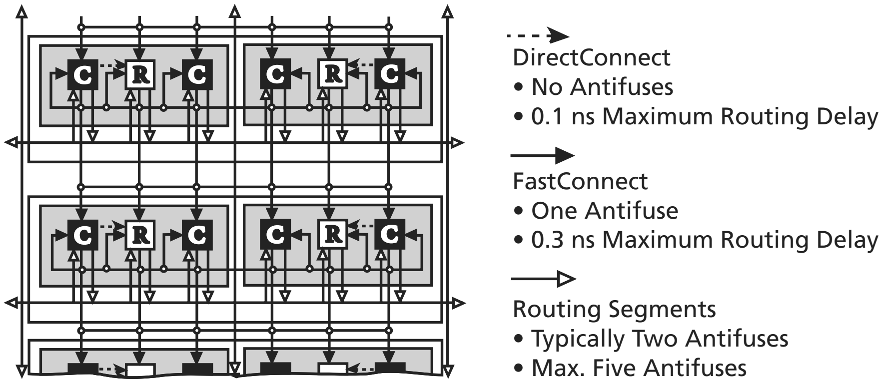


Figure 1-5 • **DirectConnect and FastConnect for Type 1 SuperClusters**

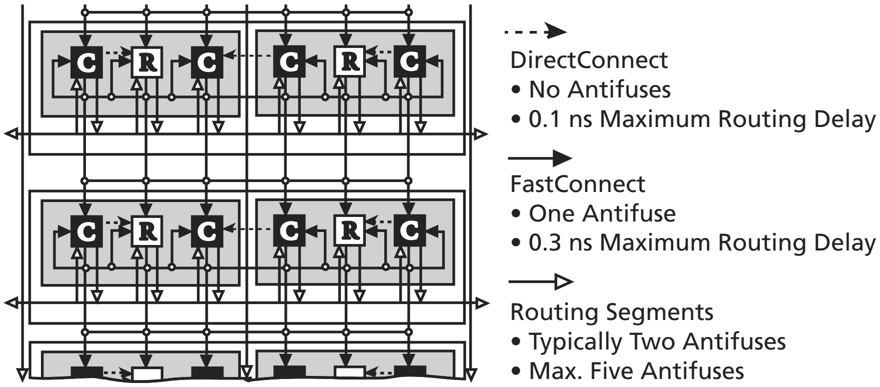


Figure 1-6 • **DirectConnect and FastConnect for Type 2 SuperClusters**

Clock Resources

Actel's high-drive routing structure provides three clock networks (Table 1-1). The first clock, called HCLK, is hardwired from the HCLK buffer to the clock select multiplexor (MUX) in each R-cell. HCLK cannot be connected to combinatorial logic. This provides a fast propagation path for the clock signal. If not used, this pin must be set as Low or High on the board. It must not be left floating. Figure 1-7 describes the clock circuit used for the constant load HCLK and the macros supported.

HCLK does not function until the fourth clock cycle each time the device is powered up to prevent false output levels due to any possible slow power-on-reset signal and fast start-up clock circuit. To activate HCLK from the first cycle, the TRST pin must be reserved in the Design software and the pin must be tied to GND on the board.

Two additional clocks (CLKA, CLKB) are global clocks that can be sourced from external pins or from internal logic signals within the SX-A device. CLKA and CLKB may be connected to sequential cells or to combinational logic. If CLKA or CLKB pins are not used or sourced from signals, these pins must be set as Low or High on the board. They must not be left floating. Figure 1-8 describes the CLKA and CLKB circuit used and the macros supported in SX-A devices with the exception of A54SX72A.

In addition, the A54SX72A device provides four quadrant clocks (QCLKA, QCLKB, QCLKC, and QCLKD—corresponding to bottom-left, bottom-right, top-left, and top-right locations on the die, respectively), which can be sourced from external pins or from internal logic signals within the device. Each of these clocks can individually drive up to an entire quadrant of the chip, or they can be grouped together to drive multiple quadrants (Figure 1-9 on page 1-6). QCLK pins can function as user I/O pins. If not used, the QCLK pins must be tied Low or High on the board and must not be left floating.

For more information on how to use quadrant clocks in the A54SX72A device, refer to the *Global Clock Networks in Actel's Antifuse Device*s and *Using A54SX72A and RT54SX72S Quadrant Clocks* application notes.

The CLKA, CLKB, and QCLK circuits for A54SX72A as well as the macros supported are shown in Figure 1-10 on page 1-6. Note that bidirectional clock buffers are only available in A54SX72A. For more information, refer to the "Pin Description" section on page 1-15.

Table 1-1 • **SX-A Clock Resources**

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Routed Clocks (CLKA, CLKB)	2	2	2	2
Hardwired Clocks (HCLK)	1	1	1	1
Quadrant Clocks (QCLKA, QCLKB, QCLKC, QCLKD)	0	0	0	4

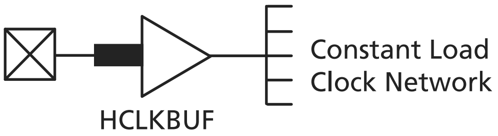


Figure 1-7 • **SX-A HCLK Clock Buffer**

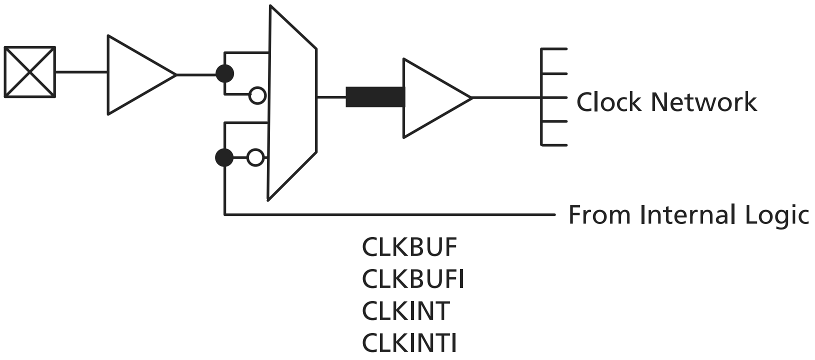


Figure 1-8 • **SX-A Routed Clock Buffer**

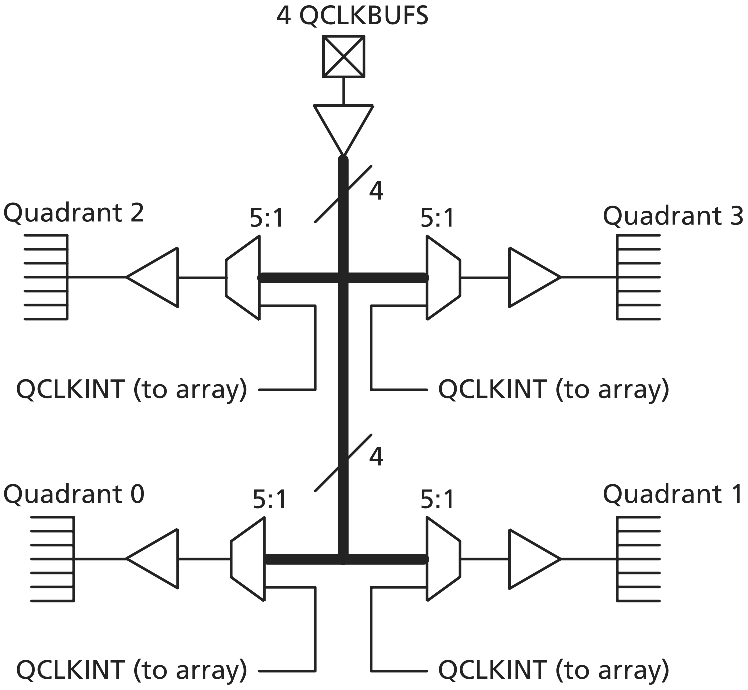


Figure 1-9 • **SX-A QCLK Architecture**

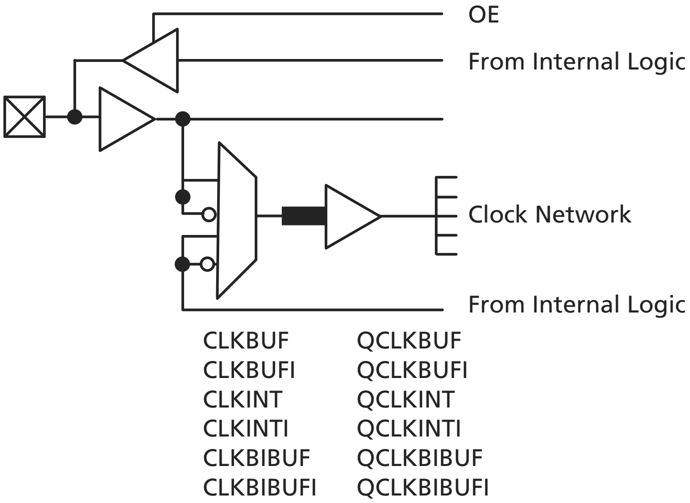


Figure 1-10 • **A54SX72A Routed Clock and QCLK Buffer**

Other Architectural Features

Technology

The Actel SX-A family is implemented on a high-voltage, twin-well CMOS process using 0.22 μ / 0.25 μ design rules. The metal-to-metal antifuse is comprised of a combination of amorphous silicon and dielectric material with barrier metals and has a programmed ('on' state) resistance of 25 Ω with capacitance of 1.0 fF for low signal impedance.

Performance

The unique architectural features of the SX-A family enable the devices to operate with internal clock frequencies of 350 MHz, causing very fast execution of even complex logic functions. The SX-A family is an optimal platform upon which to integrate the functionality previously contained in multiple complex programmable logic devices (CPLDs). In addition, designs that previously would have required a gate array to meet performance goals can be integrated into an SX-A device with dramatic improvements in cost and time-to-market. Using timing-driven place-and-route tools, designers can achieve highly deterministic device performance.

User Security

Reverse engineering is virtually impossible in SX-A devices because it is extremely difficult to distinguish between programmed and unprogrammed antifuses. In addition, since SX-A is a nonvolatile, single-chip solution, there is no configuration bitstream to intercept at device power-up.

The Actel FuseLock advantage ensures that unauthorized users will not be able to read back the contents of an Actel antifuse FPGA. In addition to the inherent strengths of the architecture, special security fuses that prevent internal probing and overwriting are hidden throughout the fabric of the device. They are located where they cannot be accessed or bypassed without destroying access to the rest of the device, making both invasive and more-subtle noninvasive attacks ineffective against Actel antifuse FPGAs.

Look for this symbol to ensure your valuable IP is secure (Figure 1-11).

Figure 1-11 • **FuseLock**

For more information, refer to Actel's *Implementation of Security in Actel Antifuse FPGAs* application note.

I/O Modules

For a simplified I/O schematic, refer to Figure 1 in the application note, *Actel eX, SX-A, and RTSX-S I/Os*.

Each user I/O on an SX-A device can be configured as an input, an output, a tristate output, or a bidirectional pin. Mixed I/O standards can be set for individual pins, though this is only allowed with the same voltage as the input. These I/Os, combined with array registers, can achieve clock-to-output-pad timing as fast as 3.8 ns, even without the dedicated I/O registers. In most FPGAs, I/O cells that have embedded latches and flip-flops, requiring instantiation in HDL code; this is a design complication not encountered in SX-A FPGAs. Fast pin-to-pin timing ensures that the device is able to interface with any other device in the system, which in turn enables parallel design of system components and reduces overall design time. All unused I/Os are configured as tristate outputs by the Actel Designer software, for maximum flexibility when designing new boards or migrating existing designs.

SX-A I/Os should be driven by high-speed push-pull devices with a low-resistance pull-up device when being configured as tristate output buffers. If the I/O is driven by a voltage level greater than V_{CCI} and a fast push-pull device is NOT used, the high-resistance pull-up of the driver and the internal circuitry of the SX-A I/O may create a voltage divider. This voltage divider could pull the input voltage below specification for some devices connected to the driver. A logic '1' may not be correctly presented in this case. For example, if an open drain driver is used with a pull-up resistor to 5 V to provide the logic '1' input, and V_{CCI} is set to 3.3 V on the SX-A device, the input signal may be pulled down by the SX-A input.

Each I/O module has an available power-up resistor of approximately 50 kΩ that can configure the I/O in a known state during power-up. For nominal pull-up and pull-down resistor values, refer to Table 1-4 on page 1-8 of the application note *Actel eX, SX-A, and RTSX-S I/Os*. Just slightly before V_{CCA} reaches 2.5 V, the resistors are disabled, so the I/Os will be controlled by user logic. See Table 1-2 on page 1-8 and Table 1-3 on page 1-8 for more information concerning available I/O features.

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a 70 Ω series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

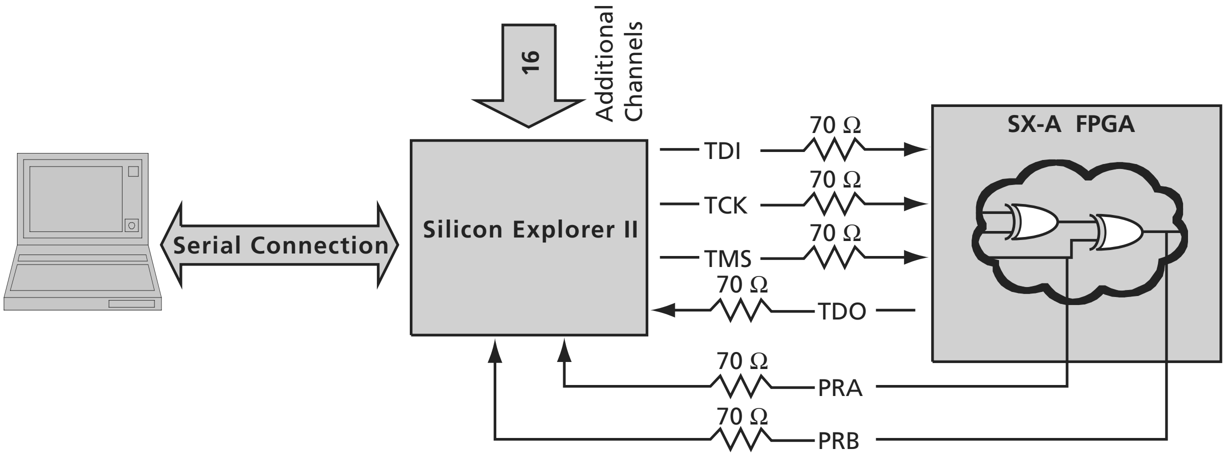


Figure 1-13 • **Probe Setup**

Related Documents

Application Notes

Global Clock Networks in Actel's Antifuse Devices
http://www.actel.com/documents/GlobalClk_AN.pdf
Using A54SX72A and RT54SX72S Quadrant Clocks
http://www.actel.com/documents/QCLK_AN.pdf
Implementation of Security in Actel Antifuse FPGAs
http://www.actel.com/documents/Antifuse_Security_AN.pdf
Actel eX, SX-A, and RTSX-S I/Os
http://www.actel.com/documents/AntifuseIO_AN.pdf
Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications
http://www.actel.com/documents/HotSwapColdSparing_AN.pdf
Programming Antifuse Devices
http://www.actel.com/documents/AntifuseProgram_AN.pdf

Datasheets

HiRel SX-A Family FPGAs
http://www.actel.com/documents/HRSXA_DS.pdf
SX-A Automotive Family FPGAs
http://www.actel.com/documents/SXA_Auto_DS.pdf

User's Guides

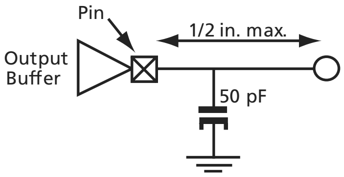
Silicon Sculptor User's Guide
http://www.actel.com/documents/SiliSculptII_Sculpt3_ug.pdf

Table 2-8 • **AC Specifications (5 V PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4$ [1]	–44	–	mA
		$1.4 \leq V_{OUT} < 2.4$ [1, 2]	$(-44 + (V_{OUT} - 1.4)/0.024)$	–	mA
		$3.1 < V_{OUT} < V_{CCI}$ [1, 3]	–	EQ 2-1 on page 2-5	–
	(Test Point)	$V_{OUT} = 3.1$ [3]	–	–142	mA
$I_{OL(AC)}$	Switching Current Low	$V_{OUT} \geq 2.2$ [1]	95	–	mA
		$2.2 > V_{OUT} > 0.55$ [1]	$(V_{OUT}/0.023)$	–	mA
		$0.71 > V_{OUT} > 0$ [1, 3]	–	EQ 2-2 on page 2-5	–
	(Test Point)	$V_{OUT} = 0.71$ [3]	–	206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load [4]	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load [4]	1	5	V/ns

Notes:

1. *Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.*
3. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
4. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.*



Where:

C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF

C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of CLKA/B in pF

C_{EQHV} = Variable capacitance of HCLK in pF

C_{EQHF} = Fixed capacitance of HCLK in pF

$C_{L =}$ Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average CLKA rate in MHz

f_{q2} = Average CLKB rate in MHz

f_{s1} = Average HCLK rate in MHz

m = Number of logic modules switching at fm

n = Number of input buffers switching at fn

p = Number of output buffers switching at fp

q_1 = Number of clock loads on CLKA

q_2 = Number of clock loads on CLKB

r_1 = Fixed capacitance due to CLKA

r_2 = Fixed capacitance due to CLKB

$s_{1 =}$ Number of clock loads on HCLK

x = Number of I/Os at logic low

y = Number of I/Os at logic high

Table 2-11 • **CEQ Values for SX-A Devices**

	A54SX08A	**A54SX16A**	**A54SX32A**	**A54SX72A**
Combinatorial modules (C_{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C_{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C_{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C_{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C_{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C_{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r_1)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

θ_{JA} = Junction-to-air thermal resistance
θ_{JC} = Junction-to-case thermal resistance
T_J = Junction temperature
T_A = Ambient temperature
T_C = Ambient temperature
P = total power dissipated by the device

Table 2-12 • **Package Thermal Characteristics**

Package Type	Pin Count	θ_{JC}	θ_{JA} Still Air	θ_{JA} 1.0 m/s 200 ft./min.	θ_{JA} 2.5 m/s 500 ft./min.	Units
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP)[1]	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader[2]	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

1. *The A54SX08A PQ208 has no heat spreader.*
2. *The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.*

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

θ_{JA} = 17.1°C/W is taken from Table 2-12 on page 2-11

T_A = 125°C is the maximum limit of ambient (from the datasheet)

$$\text{Max. Allowed Power} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{150°\text{C} - 125°\text{C}}{17.1°\text{C/W}} = 1.46\ \text{W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

T_J = 110°C

T_A = 70°C

From the datasheet:

θ_{JA} = 18.0°C/W

θ_{JC} = 3.2 °C/W

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110°\text{C} - 70°\text{C}}{18.0°\text{C/W}} = 2.22\ \text{W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{P} = \frac{110°\text{C} - 70°\text{C}}{3.00\ \text{W}} = 13.33°\text{C/W}$$

EQ 2-13

Timing Characteristics

Timing characteristics for SX-A devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX-A family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design are complete. The timing characteristics listed in this datasheet represent sample timing numbers of the SX-A devices. Design-specific delay values may be determined by using Timer or performing simulation after successful place-and-route with the Designer software.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6 percent of the nets in a design may be designated as critical, while 90 percent of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three to five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout routing delays.

Timing Derating

SX-A devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Temperature and Voltage Derating Factors

Table 2-13 • **Temperature and Voltage Derating Factors (Normalized to Worst-Case Commercial, T_J = 70°C, V_{CCA} = 2.25 V)**

V_{CCA}	Junction Temperature (T_J)						
	–55°C	–40°C	0°C	25°C	70°C	85°C	125°C
2.250 V	0.79	0.80	0.87	0.89	1.00	1.04	1.14
2.500 V	0.74	0.75	0.82	0.83	0.94	0.97	1.07
2.750 V	0.68	0.69	0.75	0.77	0.87	0.90	0.99

Timing Characteristics

Table 2-14 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25$ V, $V_{CCI} = 3.0$ V, $T_J = 70°C$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.9		1.1		1.2		1.7	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.7		0.9		1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.0		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.0		1.1		1.3		1.8	ns

Notes:

1. *For dual-module macros, use* $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, *or* $t_{PD1} + t_{RD1} + t_{SUD}$, *whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-15 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 2.25 V, T_J = 70°C)

Parameter	**Description**	**–2 Speed**		**–1 Speed**		**Std. Speed**		**–F Speed**		**Units**
		Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
Dedicated (Hardwired) Array Clock Networks										
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.4		1.6		1.8		2.6	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.3		1.5		1.7		2.4	ns
t_{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.7	ns
t_{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.1		1.3		1.8	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.0		1.1		1.3		1.8	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.4	ns
t_{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t_{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t_{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-17 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)

		–2 Speed		–1 Speed		Std. Speed		–F Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Dedicated (Hardwired) Array Clock Networks										
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t_{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t_{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t_{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t_{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t_{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-21 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[2]												
t_{PD}	Internal Array Module		0.9		1.0		1.2		1.4		1.9	ns
Predicted Routing Delays[3]												
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns
R-Cell Timing												
t_{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.8		1.0		1.4	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.6		1.9		2.7		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Minimum Pulse Width	1.4		1.7		1.9		2.2		3.0		ns
Input Module Propagation Delays												
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.5		0.6		0.7		0.8		1.1	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		0.8		0.9		1.0		1.1		1.6	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.8		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		0.9		1.1		1.2		1.4		2.0	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-28 • **A54SX32A Timing Characteristics (Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
C-Cell Propagation Delays[2]												
t_{PD}	Internal Array Module		0.8		0.9		1.1		1.2		1.7	ns
Predicted Routing Delays[3]												
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns
R-Cell Timing												
t_{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.6		0.7		0.7		0.9		1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.6		0.7		0.8		0.9		1.2		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.2		1.4		1.5		1.8		2.5		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Pulse Width	1.4		1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays												
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.6		0.7		0.8		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.2		1.3		1.5		1.8		2.5	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.6		0.7		0.8		0.9		1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.8		0.9		1.0		1.2		1.6	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.4		1.6		1.8		2.2		3.0	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-41 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.7		3.1		3.5		4.1		5.7	ns
t_{DHL}	Data-to-Pad High to Low		3.4		3.9		4.4		5.1		7.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.7		3.1		3.5		4.1		5.7	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.4		3.9		4.4		5.1		7.2	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.1		3.7		5.1	ns
t_{DHL}	Data-to-Pad High to Low		3.1		3.5		4.0		4.7		6.6	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		7.4		8.5		9.7		11.4		15.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.1		3.7		5.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.1		3.5		4.0		4.7		6.6	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

329-Pin PBGA	
Pin Number	**A54SX32A Function**
D11	V_{CCA}
D12	NC
D13	I/O
D14	I/O
D15	I/O
D16	I/O
D17	I/O
D18	I/O
D19	I/O
D20	I/O
D21	I/O
D22	I/O
D23	I/O
E1	V_{CCI}
E2	I/O
E3	I/O
E4	I/O
E20	I/O
E21	I/O
E22	I/O
E23	I/O
F1	I/O
F2	TMS
F3	I/O
F4	I/O
F20	I/O
F21	I/O
F22	I/O
F23	I/O
G1	I/O
G2	I/O
G3	I/O
G4	I/O
G20	I/O
G21	I/O
G22	I/O
G23	GND
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H20	V_{CCA}
H21	I/O
H22	I/O
H23	I/O
J1	NC
J2	I/O
J3	I/O
J4	I/O
J20	I/O
J21	I/O
J22	I/O
J23	I/O
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K10	GND
K11	GND
K12	GND
K13	GND
K14	GND
K20	I/O
K21	I/O
K22	I/O
K23	I/O
L1	I/O
L2	I/O
L3	I/O
L4	NC
L10	GND
L11	GND
L12	GND
L13	GND
L14	GND
L20	NC
L21	I/O
L22	I/O
L23	NC
M1	I/O
M2	I/O
M3	I/O
M4	V_{CCA}
M10	GND
M11	GND
M12	GND
M13	GND
M14	GND
M20	V_{CCA}
M21	I/O
M22	I/O
M23	V_{CCI}
N1	I/O
N2	TRST, I/O
N3	I/O
N4	I/O
N10	GND
N11	GND
N12	GND
N13	GND
N14	GND
N20	NC
N21	I/O
N22	I/O
N23	I/O
P1	I/O
P2	I/O
P3	I/O
P4	I/O
P10	GND
P11	GND
P12	GND
P13	GND
P14	GND
P20	I/O
P21	I/O
P22	I/O
P23	I/O
R1	I/O
R2	I/O
R3	I/O
R4	I/O
R20	I/O
R21	I/O
R22	I/O
R23	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T20	I/O
T21	I/O
T22	I/O
T23	I/O
U1	I/O
U2	I/O
U3	V_{CCA}
U4	I/O
U20	I/O
U21	V_{CCA}
U22	I/O
U23	I/O
V1	V_{CCI}
V2	I/O
V3	I/O
V4	I/O
V20	I/O
V21	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V_{CCI}	V_{CCI}	V_{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V_{CCI}	V_{CCI}	V_{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V_{CCI}	V_{CCI}	V_{CCI}
L8	V_{CCI}	V_{CCI}	V_{CCI}
L9	V_{CCI}	V_{CCI}	V_{CCI}
L10	V_{CCI}	V_{CCI}	V_{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V_{CCA}	V_{CCA}	V_{CCA}
P14	I/O	I/O	I/O

484-Pin FBGA

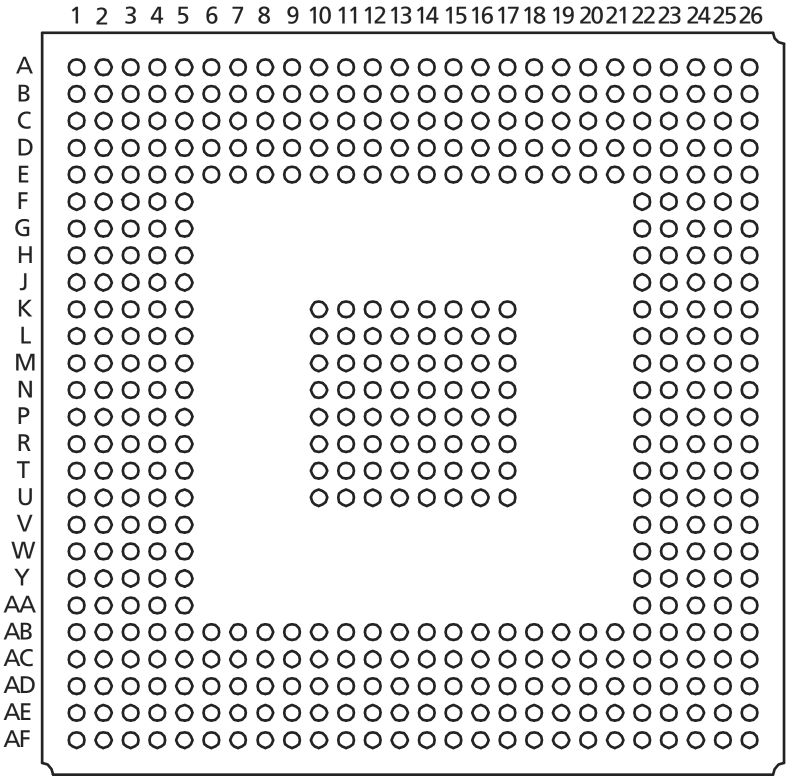


Figure 3-8 • **484-Pin FBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.